



POWER MOSFET THRU-HOLE (TO-254AA)

500V, N-CHANNEL HEXFET MOSFET TECHNOLOGY

Product Summary

Part Number	R _{DS(on)}	I _D		
IRFM460	0.27Ω	19A		



Description

HEXFET MOSFET technology is the key to IR HiRel advanced line of power MOSFET transistors. The efficient geometry design achieves very low on-state resistance combined with high trans conductance. HEXFET transistors also feature all of the well-established advantages of MOSFETs, such as voltage control, very fast switching, and electrical parameter temperature stability. They are well-suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers, high energy pulse circuits, and virtually any application where high reliability is required. The HEXFET transistor's totally isolated package eliminates the need for additional isolating material between the device and the heat sink. This improves thermal efficiency and reduces drain capacitance.

Features

- Simple Drive Requirements
- Hermetically Sealed
- Dynamic dv/dt Rating
- Light Weight

Absolute Maximum Ratings

Symbol	Parameter	Value	Units	
I_{D1} @ V_{GS} = 10V, T_{C} = 25°C	Continuous Drain Current	19		
I _{D2} @ V _{GS} = 10V, T _C = 100°C	Continuous Drain Current	12	Α	
I _{DM} @T _C = 25°C	Pulsed Drain Current ①	76		
P _D @T _C = 25°C	Maximum Power Dissipation	250	W	
	Linear Derating Factor	2.0	W/°C	
V_{GS}	Gate-to-Source Voltage	± 20	V	
E _{AS}	Single Pulse Avalanche Energy ②	1200	mJ	
I _{AR}	Avalanche Current ①	19	Α	
E _{AR}	Repetitive Avalanche Energy ①	25	mJ	
dv/dt	Peak Diode Recovery dv/dt ③	3.5	V/ns	
T _J	Operating Junction and	-55 to + 150		
T _{STG}	Storage Temperature Range	-33 10 + 130	°C	
	Lead Temperature	300 (0.063 in. /1.6 mm from case for 10s)		
	Weight	9.3 (Typical)	g	

For Footnotes refer to the page 2.



Electrical Characteristics @ T_j = 25°C (Unless Otherwise Specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
BV _{DSS}	Drain-to-Source Breakdown Voltage	500			V	$V_{GS} = 0V, I_{D} = 1.0mA$
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.68		V/°C	Reference to 25°C, I _D = 1.0mA
В	Static Drain-to-Source On-State			0.27	Ω	V _{GS} = 10V, I _{D2} = 12A ④
$R_{DS(on)}$	Resistance			0.31	5.2	V _{GS} = 10V, I _{D1} = 19A ④
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
Gfs	Forward Transconductance	13			S	V _{DS} = 15V, I _{D2} = 12A ④
I _{DSS}	Zero Gate Voltage Drain Current			25	μA	$V_{DS} = 400V, V_{GS} = 0V$
	Zero Gate Voltage Brain Gurrent			250	μΛ	$V_{DS} = 400V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I_{GSS}	Gate-to-Source Leakage Forward			100	nA	V _{GS} = 20V
	Gate-to-Source Leakage Reverse			-100	П	$V_{GS} = -20V$
Q_{G}	Total Gate Charge			190		I _{D1} = 19A
Q_GS	Gate-to-Source Charge			27	nC	V _{DS} = 250V
Q_{GD}	Gate-to-Drain ('Miller') Charge			135		V _{GS} = 10V
t _{d(on)}	Turn-On Delay Time			35		V _{DD} = 250V
tr	Rise Time			120	no	I _{D1} = 19A
$t_{d(off)}$	Turn-Off Delay Time			130	ns	$R_G = 2.35\Omega$
t _f	Fall Time			98		V _{GS} = 10V
Ls +L _D	Total Inductance		6.8		nH	Measured from Drain lead (6mm / 0.25 in from package) to Source lead (6mm/ 0.25 in from package) with Source wire internally bonded from Source pin to Drain pad
C _{iss}	Input Capacitance		4300			V _{GS} = 0V
C _{oss}	Output Capacitance		1000		рF	V _{DS} = 25V
C _{rss}	Reverse Transfer Capacitance		250			f = 1.0MHz

Source-Drain Diode Ratings and Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
Is	Continuous Source Current (Body Diode)			19	۸	
I _{SM}	Pulsed Source Current (Body Diode) ①			76	Α	
V_{SD}	Diode Forward Voltage			1.8	V	$T_J = 25^{\circ}C, I_S = 19A, V_{GS} = 0V$
t _{rr}	Reverse Recovery Time			580	ns	$T_J = 25^{\circ}C, I_F = 19A, V_{DD} \le 50V$
Q _{rr}	Reverse Recovery Charge			8.1	μC	di/dt = 100A/µs ④
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)				

Thermal Resistance

Symbol	Parameter	Min.	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case			0.5	
$R_{\theta CS}$	Case -to-Sink		0.21		°C/W
$R_{\theta JA}$	Junction-to-Ambient (Typical socket mount)			48	

Footnotes:

- ① Repetitive Rating; Pulse width limited by maximum junction temperature.
- $^{\circ}$ V_{DD} = 50V, starting T_J = 25°C, L = 6.6mH, Peak I_L = 19A, V_{GS} = 10V
- $\label{eq:local_spin_spin} \ \, J_{SD} \leq 19A, \, di/dt \leq 160A/\mu s, \, V_{DD} \leq 500V, \, T_J \leq 150^{\circ}C$
- 4 Pulse width $\leq 300 \ \mu s$; Duty Cycle $\leq 2\%$.



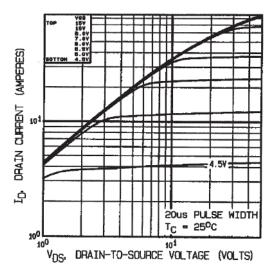


Fig 1. Typical Output Characteristics

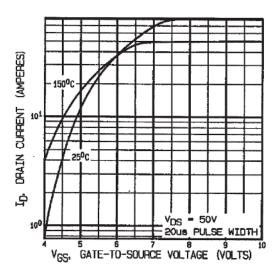


Fig 3. Typical Transfer Characteristics

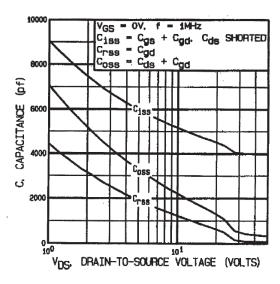


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

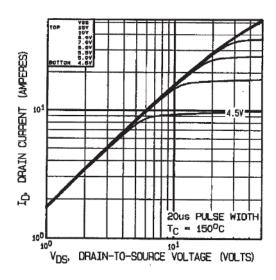


Fig 2. Typical Output Characteristics

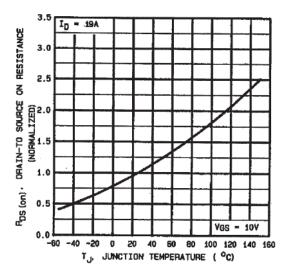


Fig 4. Normalized On-Resistance Vs. Temperature

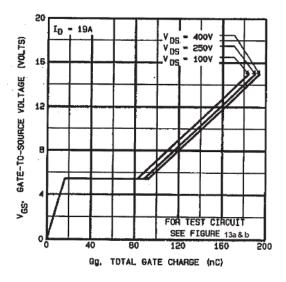


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

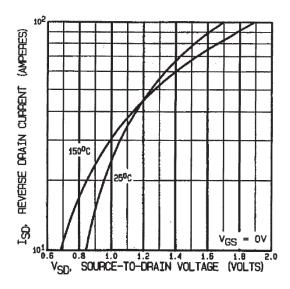


Fig 7. Typical Source-Drain Diode Forward Voltage

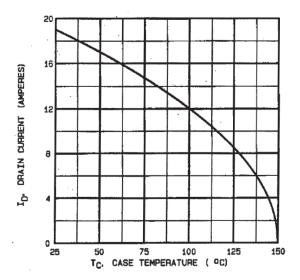


Fig 9. Maximum Drain Current Vs. Case Temperature

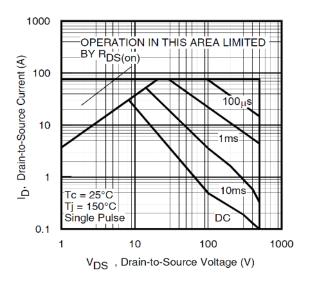


Fig 8. Maximum Safe Operating Area

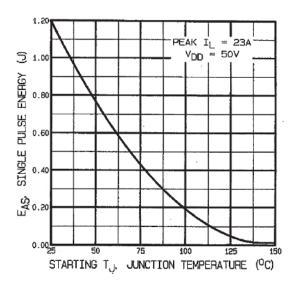


Fig 10. Maximum Avalanche Energy Vs. Drain Current

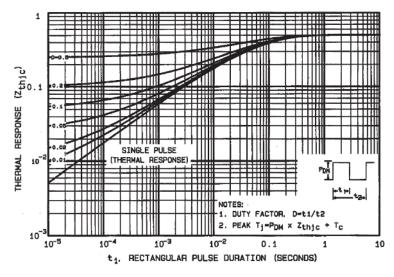


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

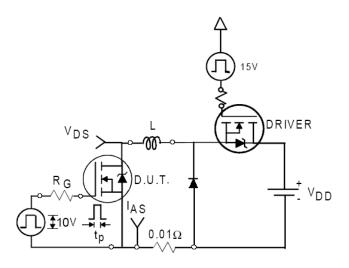


Fig 12a. Unclamped Inductive Test Circuit

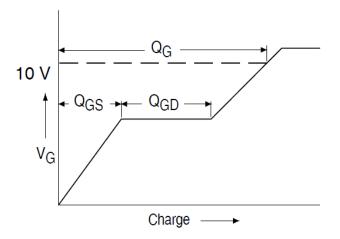


Fig 13a. Basic Gate Charge Waveform

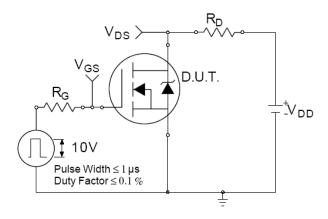


Fig 14a. Switching Time Test Circuit

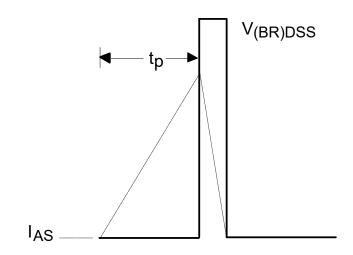


Fig 12b. Unclamped Inductive Waveforms

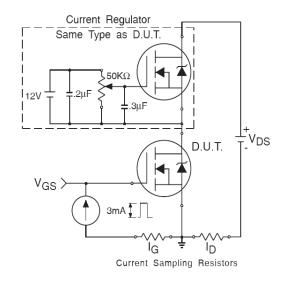


Fig 13b. Gate Charge Test Circuit

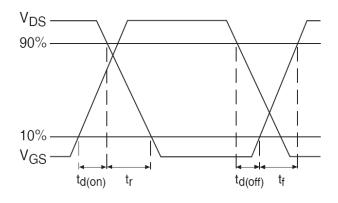
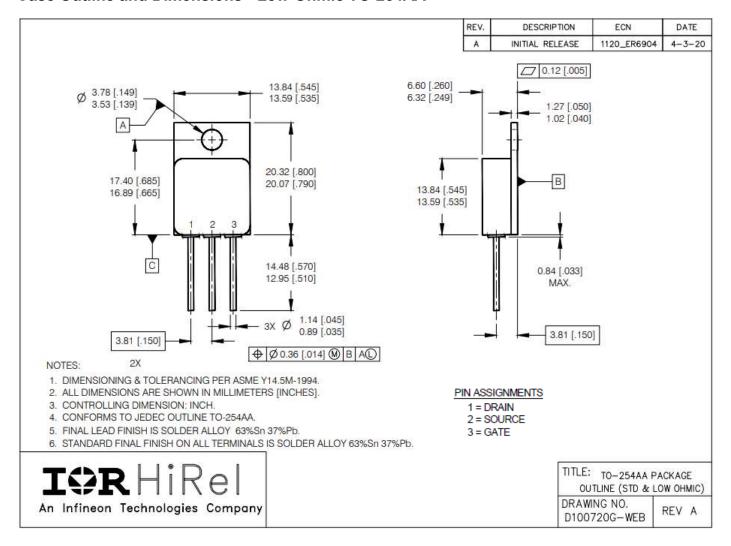


Fig 14b. Switching Time Waveforms



Note: For the most updated package outline, please see the website: TO-254AA

Case Outline and Dimensions - Low-Ohmic TO-254AA



BERYLLIA WARNING PER MIL-PRF-19500

Package containing beryllia shall not be ground, sandblasted, machined, or have other operations performed on them which will produce beryllia or beryllium dust. Furthermore, beryllium oxide packages shall not be placed in acids that will produce fumes containing beryllium.



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